Application/Control No. Applicant(s)/Patent Under Reexamination 10/075,963 DAY, MARK Notice of References Cited Art Unit Examiner Page 1 of 1 Van Kim T. Nguyen 2151 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,732,175 05-2004 Abjanic, John B. Α 709/227 US-В US-С D US-Ε US-F US-US-G US-Н US-1 J US-Κ US-US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U V W

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